

NDS8433 Single P-Channel Enhancement Mode Field Effect Transistor

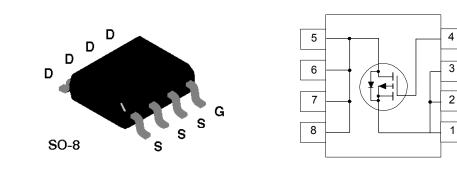
General Description

transients are needed.

Features

- These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to
- -5.2A, -20V. $R_{DS(ON)} = 0.055\Omega$ @ $V_{GS} = -4.5V$ $R_{DS(ON)} = 0.075\Omega$ @ $V_{GS} = -2.7V$.
 - High density cell design for extremely low R_{DS(ON)}.
 - High power and current handling capability in a widely used surface mount package.

June 1996

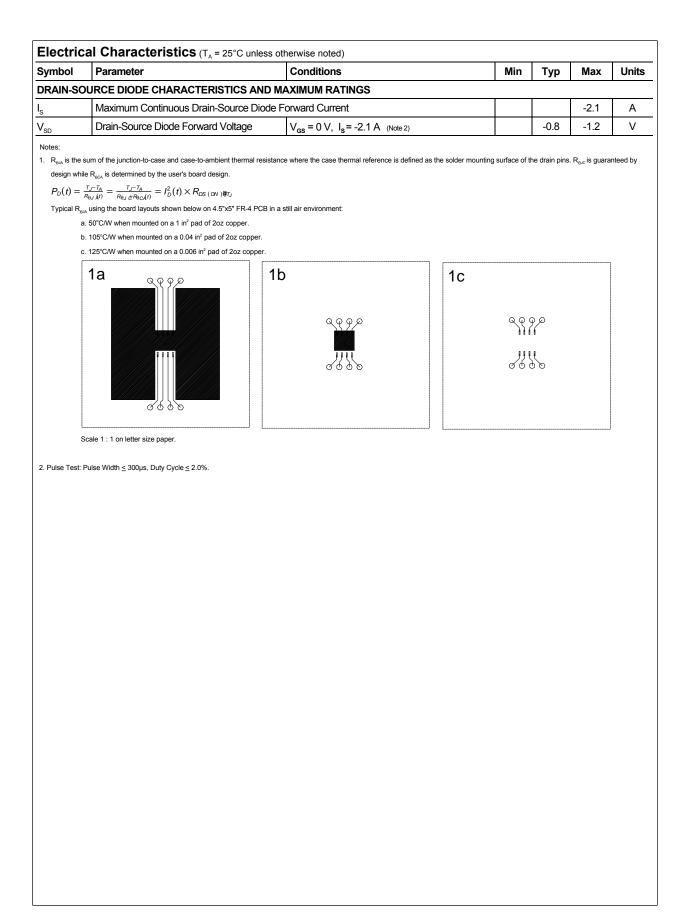


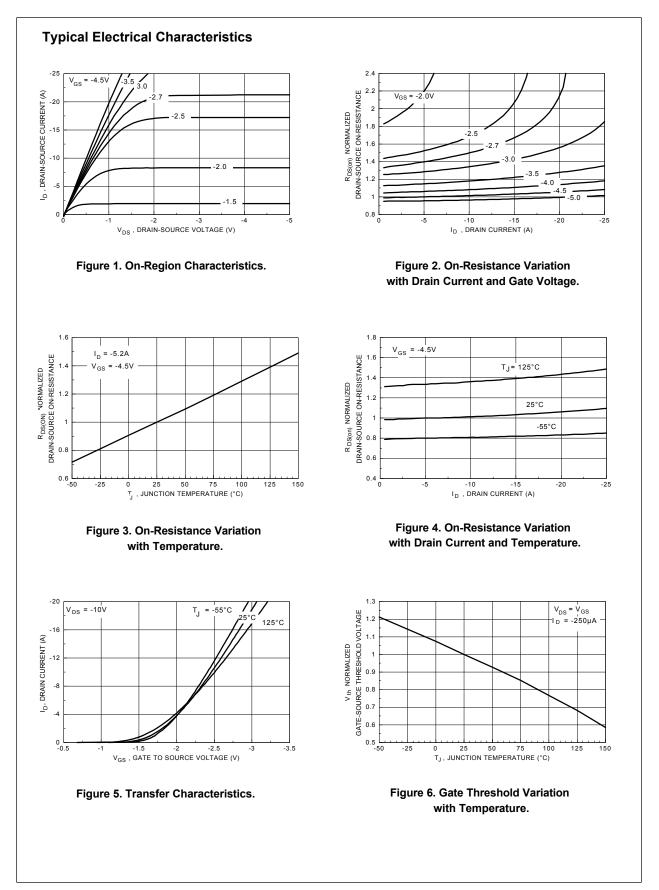
Absolute Maximum Ratings T_a = 25°C unless otherwise noted

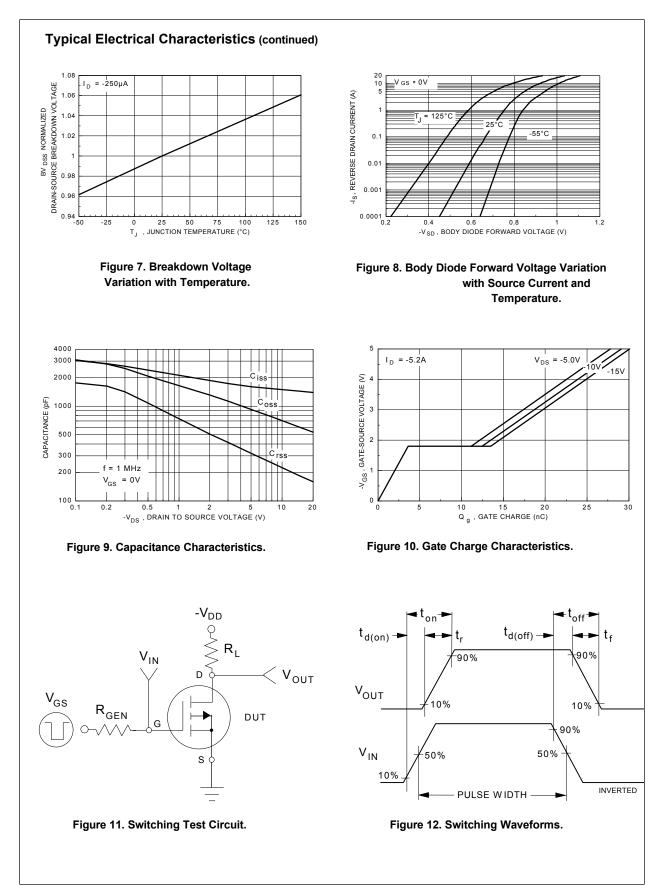
Symbol	Parameter		NDS8433	Units
V _{DSS}	Drain-Source Voltage		-20	V
/ _{GSS}	Gate-Source Voltage		-8	V
D	Drain Current - Continuous	(Note 1a)	-5.2	А
	- Pulsed		-20	
D	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
J,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
HERMA	L CHARACTERISTICS			
۲ _{өја}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
ς ^{θηC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

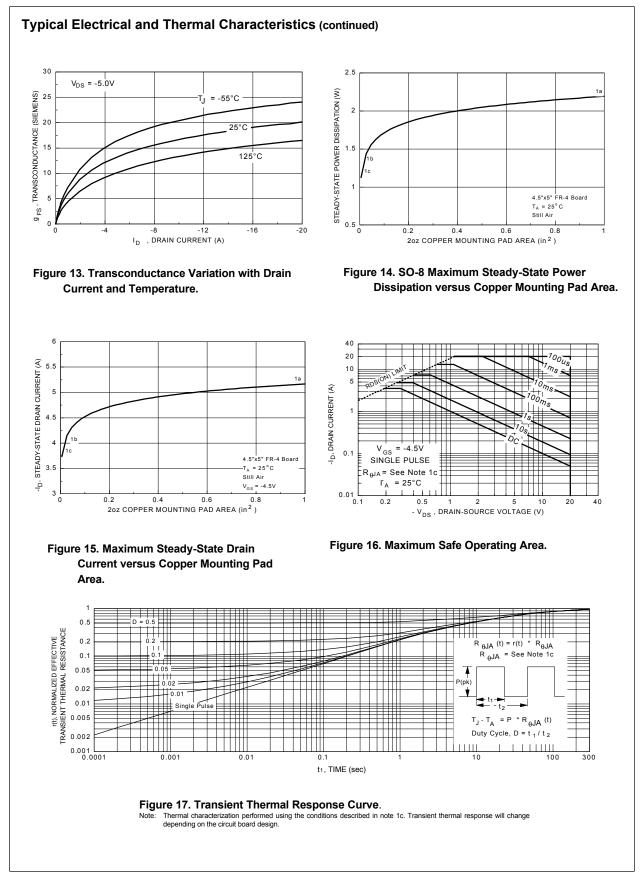
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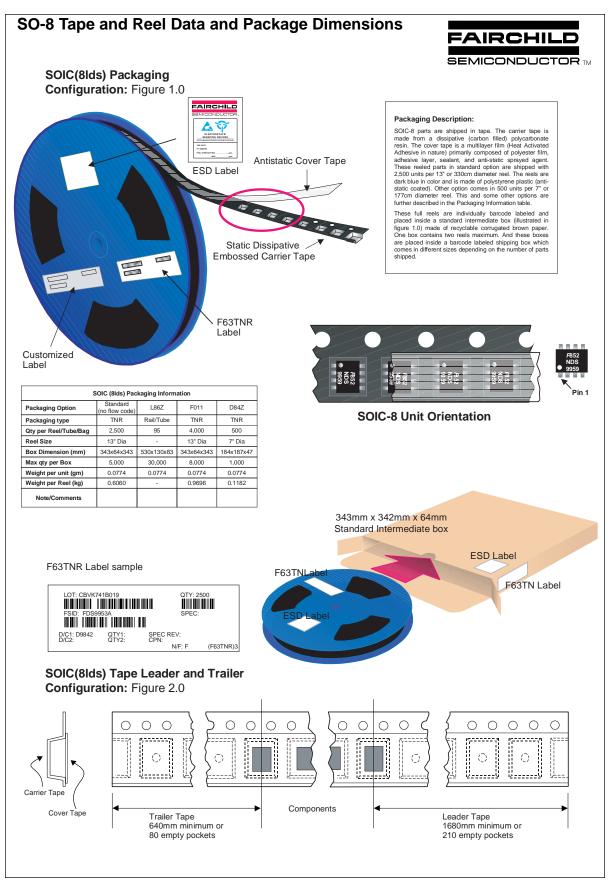
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{gs} = 0 V, I _p = -250 μA		-20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V				-1	μA
			T _J = 55°C			-10	μA
I _{GSSF}	Gate - Body Leakage, Forward	V _{gs} = 8 V, V _{ps} = 0 V				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{gs} = -8 V, V _{ps} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-0.4	-0.8	-1	V
(-)			T _J = 125°C	-0.3	-0.53	-0.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{gs} = -4.5 V, I _p = -5.2 A			0.045	0.055	Ω
			T _J = 125°C		0.06	0.11	
		V _{gs} = -2.7 V, I _p = -4.6 A			0.062	0.075	
I _{D(on)}	On-State Drain Current	V_{GS} = -4.5 V, V_{DS} = -5 V		-10			Α
		V_{GS} = -2.7 V, V_{DS} = -5 V		-5			
9 _{FS}	Forward Transconductance	$V_{\rm DS}$ = -10 V, I _D = -5.2 A			13		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	V _{DS} = -10 V, V _{GS} = 0 V, f = 1.0 MHz			1500		pF
C _{oss}	Output Capacitance				710		pF
C _{rss}	Reverse Transfer Capacitance				230		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)					-	
t _{D(on)}	Tum - On Delay Time	$V_{DD} = -5 V, I_{D} = -1 A,$ $V_{GEN} = -4.5 V, R_{GEN} = 6 \Omega$			16	30	ns
ţ	Turn - On Rise Time				41	60	ns
t _{D(off)}	Turn - Off Delay Time				100	150	ns
t _r	Turn - Off Fall Time				50	80	ns
Q _g	Total Gate Charge	V _{DS} = -5 V,			25	40	nC
Q_{gs}	Gate-Source Charge	$I_{\rm D}^{\rm SS}$ = -5.2 Å, $V_{\rm GS}$ = -4.5 V			3.6		nC
Q _{gd}	Gate-Drain Charge				7.6		nC



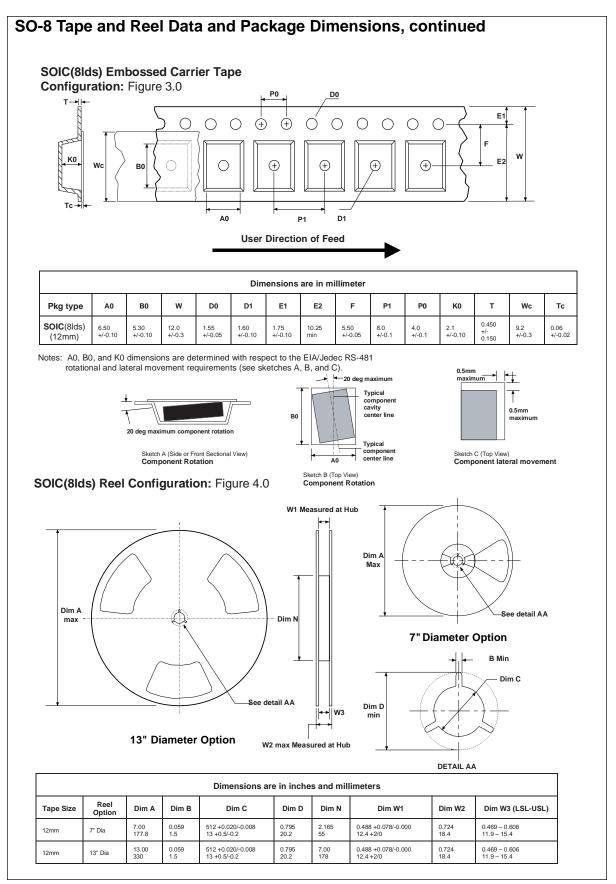


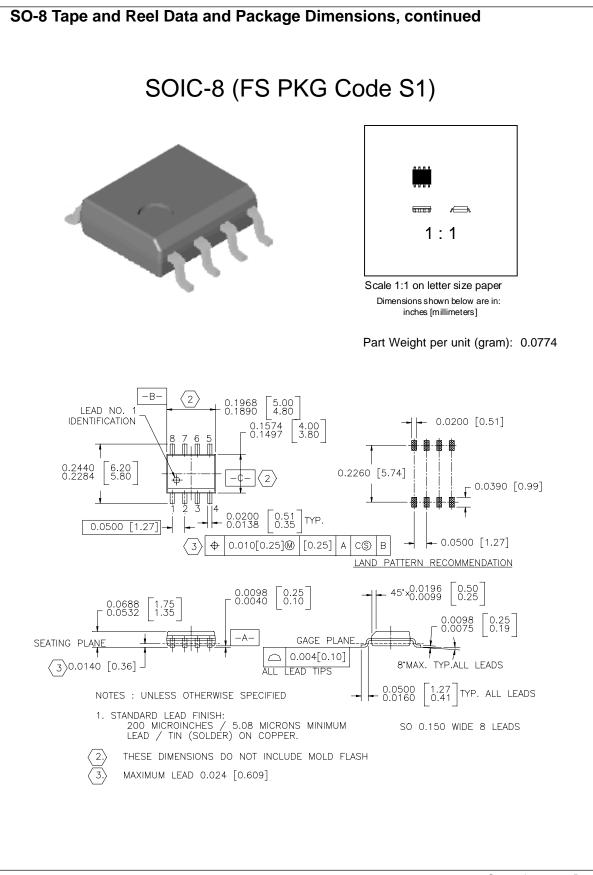






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